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# U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10058544	FILING DATE 01/25/2002	CLASS 324	SUBCLASS 754.000	GAU 2829	EXAMINER TANG, M
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**\*\*APPLICANTS:** Scott Mitchell; Reynaldo Rincon; Jerry Broz; Gerard Laugier;

**\*\*CONTINUING DATA VERIFIED:** *None ALT*

**\*\* FOREIGN APPLICATIONS VERIFIED:** *None ALT*

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

☐ yes ☒ no

35 USC 119 conditions met

☐ yes ☒ no

Verified and Acknowledged Examiners's initials

*ALT*

ATTORNEY DOCKET NO

TI-32531

**TITLE :** Multiple contact vertical probe solution enabling kelvin connection benefits for conductive bump probing

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		Application Examiner	
		<b>PREPARED FOR ISSUE</b>	
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